



## VEpioneer®

**VEpioneer®** is an unique combination of optical spectroscopy & imaging to objectively assess the entire (wafer) surface, in a fast non-invasive manner.

Contamination and deviations in production no longer have to be checked on a random basis or with time-consuming single-point measurements.

**VEpioneer®** improves manufacturing capacity by reducing reject rates during production through rapid full-field wafer inspection of a wide range of quality features in a variety of process steps.

### Matched quality features

layer thickness, homogeneity, surface energy,  
contamination, geometry, chemical composition ... **and more**

### Matched process steps

lithography, deposition processes, cleaning,  
etching, polishing, implanting, metallization ... **and more**



Surface



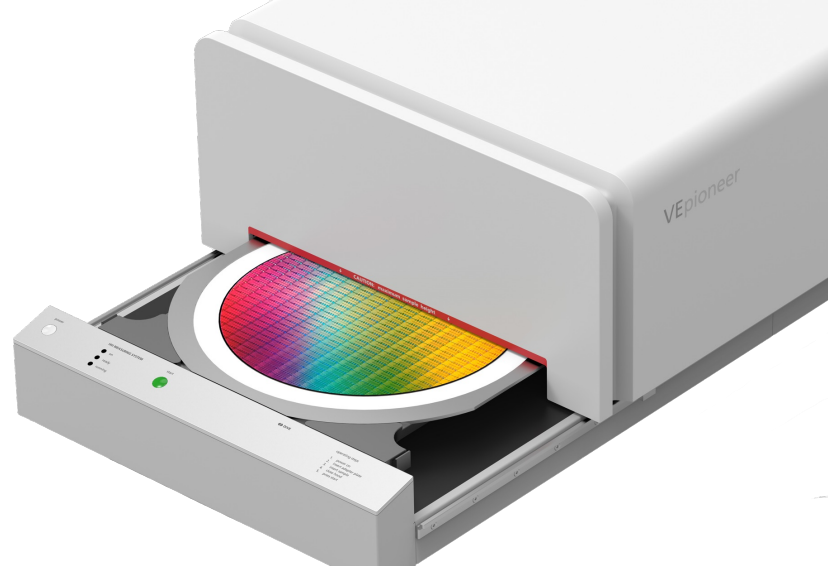
Layers and  
thin films



Defects



Process  
monitoring



VE pioneer®

## EFFICIENT SEMICONDUCTOR MANUFACTURING RESOURCE-SAVING PRODUCTION COST REDUCTION

VE pioneer®	Technical data sheet
Spatial resolution	293 µm
Software suite	VEsolve®
... incl. AI and machine learning	✓
... incl. image corrections	✓
Clean room capability	Q2/2024
Fast inspection	✓ (30 s)
200 mm wafer capabilities	✓
300 mm wafer capabilities	✓
... including wafer frame	✓
Connections	power (230 V), RJ45 (Ethernet)
System footprint	1000 x 500 mm
System height	350 mm
System weight	45 kg
Operating conditions	+5 ... +40 °C (non-condensing)

### COMPREHENDING THE INVISIBLE!